BT151-500L

SCR, 12 A, 5mA, 500 V, SOT78 Rev. 05 — 2 March 2009

Product data sheet

Product profile 1.

1.1 General description

Planar passivated SCR (Silicon Controlled Rectifier) in a SOT78 plastic package.

1.2 Features and benefits

- High reliability
- High surge current capability
- High thermal cycling performance

1.3 Applications

- Ignition circuits
- Motor control

- Protection Circuits
- Static switching

1.4 Quick reference data

Table 1. **Quick reference**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	-	500	V
$I_{T(AV)}$	average on-state current	half sine wave; T _{mb} ≤ 109 °C; see <u>Figure 3</u>	-	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; T _{mb} ≤ 109 °C; see <u>Figure 1;</u> see <u>Figure 2</u>	-	-	12	Α
Static ch	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } T_j = 25 \text{ °C;}$ $I_T = 100 \text{ mA; see } \frac{\text{Figure 8}}{\text{ or } 100 \text{ mA;}}$	-	2	5	mA



2. Pinning information

Table 2. Pinning information

		·····o······ation		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		. N
2	А	anode	mb	A → K
3	G	gate		G sym037
mb	mb	anode	1 2 3	
			SOT78 (TO-220AB;SC-46)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BT151-500L	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	500	V
V_{RRM}	repetitive peak reverse voltage		-	500	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 109 °C; see <u>Figure 3</u>	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 109 ^{\circ}\text{C}$; see Figure 1; see Figure 2	-	12	Α
dI _T /dt	rate of rise of on-state current	$I_T = 20 \text{ A}$; $I_G = 50 \text{ mA}$; $dI_G/dt = 50 \text{ mA/}\mu\text{s}$	-	50	A/μs
I _{GM}	peak gate current		-	2	Α
P_{GM}	peak gate power		-	5	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C
I _{TSM}	non-repetitive peak	half sine wave; $t_p = 8.3 \text{ ms}$; $T_{j(init)} = 25 \text{ °C}$	-	132	Α
	on-state current	half sine wave; $t_p = 10$ ms; $T_{j(init)} = 25$ °C; see Figure 4; see Figure 5	-	120	Α
I ² t	I2t for fusing	t _p = 10 ms; sine-wave pulse	-	72	A ² s
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
V_{RGM}	peak reverse gate voltage		-	5	V

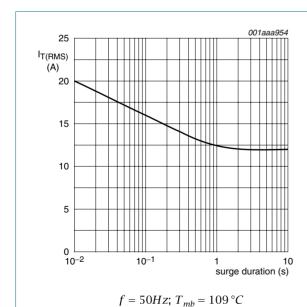


Fig 1. RMS on-state current as a function of surge duration; maximum values

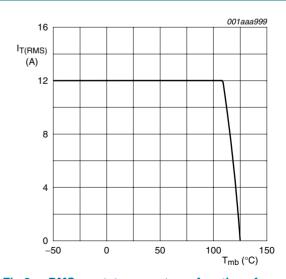


Fig 2. RMS on-state current as a function of mounting base temperature; maximum values

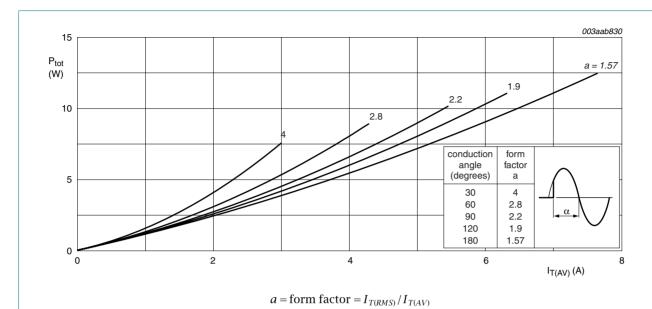


Fig 3. Total power dissipation as a function of average on-state current; maximum values

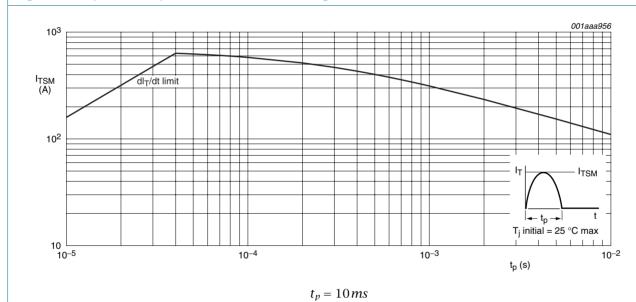


Fig 4. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

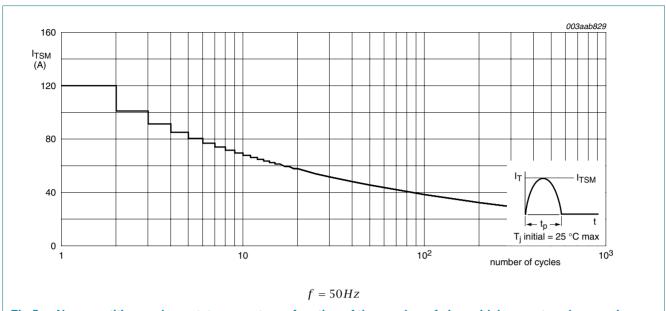
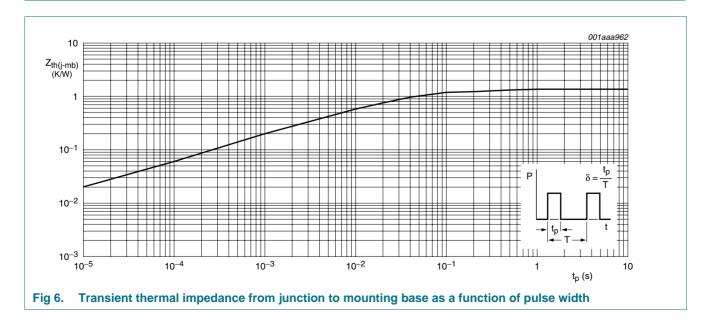


Fig 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 6	-	-	1.3	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air		-	60	-	K/W



6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; I_T = 100 \text{ mA}; \text{see}$ Figure 8	-	2	5	mA
IL	latching current	$V_D = 12 \text{ V; } T_j = 25 \text{ °C; see } \frac{\text{Figure 9}}{}$	-	10	40	mA
I _H	holding current	$V_D = 12 \text{ V; } T_j = 25 \text{ °C; see } \frac{\text{Figure 10}}{\text{ or } T_j}$	-	7	20	mΑ
V_{T}	on-state voltage	$I_T = 23 \text{ A}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 11}{}$	-	1.4	1.75	V
V_{GT}	gate trigger voltage	I_T = 100 mA; V_D = 12 V; T_j = 25 °C; see Figure 12	-	0.6	1.5	V
		$I_T = 100 \text{ mA}; V_D = 500 \text{ V}; T_j = 125 \text{ °C}$	0.25	0.4	-	V
I _D	off-state current	V _D = 500 V; T _j = 125 °C	-	0.1	0.5	mA
I_R	reverse current	V _R = 500 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic o	characteristics					
dV _D /dt rate of rise of off-state voltage		V_{DM} = 335 V; T_j = 125 °C; exponential waveform; gate open circuit	50	130	-	V/µs
		V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; exponential waveform; see Figure 7	200	1000	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; V_D = 500 \text{ V}; I_G = 100 \text{ mA};$ $dI_G/dt = 5 \text{ A/}\mu\text{s}; T_j = 25 \text{ °C}$	-	2	-	μs
t _q	commutated turn-off time	V_{DM} = 335 V; T_j = 125 °C; I_{TM} = 20 A; V_R = 25 V; $(dI_T/dt)_M$ = 30 A/ μ s; dV_D/dt = 50 V/ μ s; R_{GK} = 100 Ω	-	70	-	μs

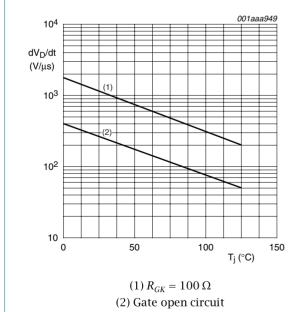


Fig 7. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

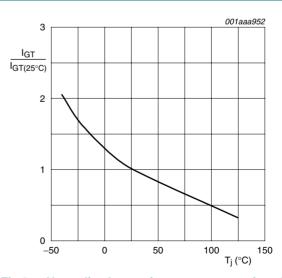


Fig 8. Normalized gate trigger current as a function of junction temperature

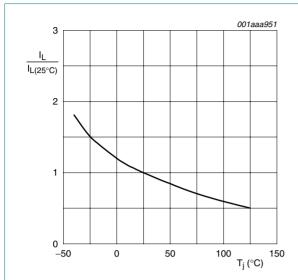


Fig 9. Normalized latching current as a function of junction temperature

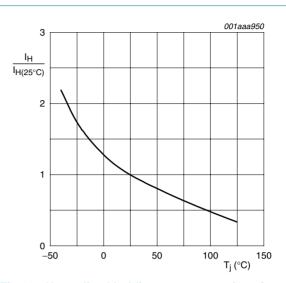
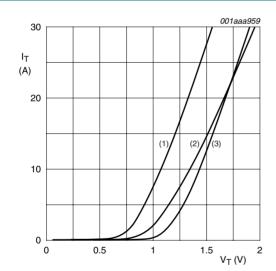


Fig 10. Normalized holding current as a function of junction temperature



 $V_0 = 1.06 \ V; R_s = 0.0304 \ \Omega$ (1) $T_j = 150 \ ^{\circ}C;$ typical values (2) $T_j = 150 \ ^{\circ}C;$ maximum values (3) $T_j = 25 \ ^{\circ}C;$ maximum values

Fig 11. On-state current as a function of on-state voltage

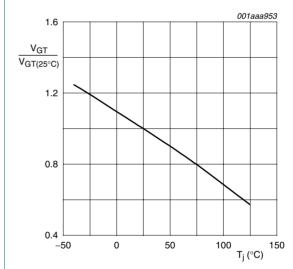


Fig 12. Normalized gate trigger voltage as a function of junction temperature

7. Package outline

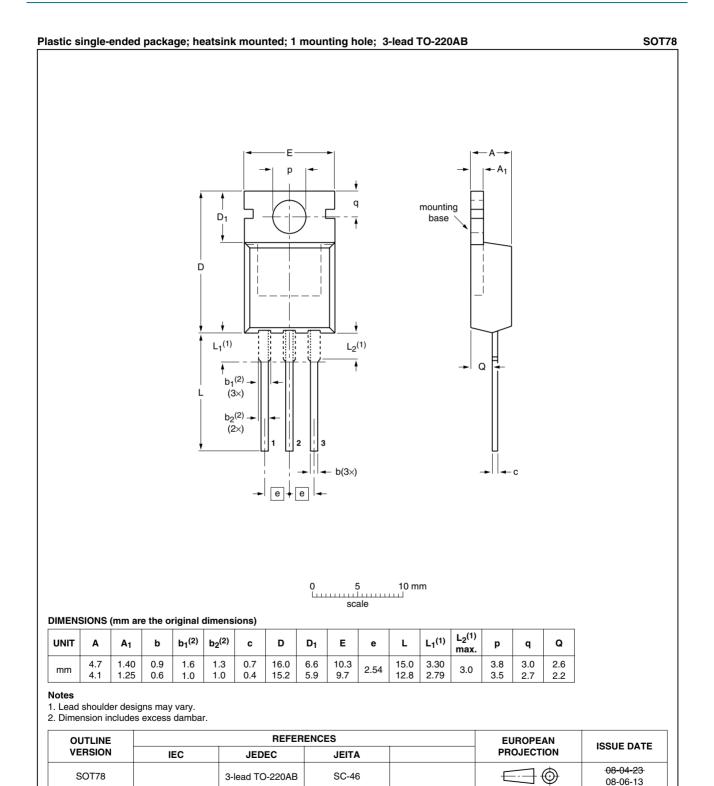


Fig 13. Package outline SOT78 (TO-220AB)

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Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Dalagas data			
	Release date	Data sheet status	Change notice	Supersedes
BT151-500L_5	20090302	Product data sheet	-	BT151_SER_L_R_4
Modifications:	 Package ou 	utline updated.		
	 Type numb 	er BT151-500L separated	from data sheet BT151	_SER_L_R_4.
BT151_SER_L_R_4	20061023	Product data sheet	-	BT151_SERIES_3
BT151_SERIES_3 (9397 750 13159)	20040607	Product specification	-	BT151_SERIES_2
BT151_SERIES_2	19990601	Product specification	-	BT151_SERIES_1
BT151_SERIES_1	19970901	Product specification	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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